

An American National Standard

IEEE Standard Test Procedures for Semiconductor X-Ray Energy Spectrometers

Sponsor

**Nuclear Instruments and Detectors Committee
of the
IEEE Nuclear and Plasma Sciences Society**

Secretariat

Institute of Electrical and Electronic Engineers, Inc

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Foreword

(This Foreword is not a part of ANSI/IEEE Std 759-1984, IEEE Standard Test Procedures for Semiconductor Energy X-Ray Spectrometers.)

This document presents standard test procedures for semiconductor X-ray energy spectrometers. Such systems consist of a semiconductor radiation detector assembly and signal processing electronics interfaced to a pulse height analyzer/computer. Companion documents are ANSI/IEEE Std 300-1982, IEEE Standard Test Procedures for Semiconductor Charged-Particle Detectors, ANSI/IEEE Std 301-1976, IEEE Standard Test Procedures for Amplifiers and Preamplifiers for Semiconductor Radiation Detectors for Ionizing Radiation, and ANSI/IEEE Std 325-1971, IEEE Standard Test Procedures for Germanium Gamma-Ray Detectors.

When this standard was approved, the Nuclear Instruments and Detectors Committee of the IEEE Nuclear and Plasma Sciences Society had the following membership:

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